

## Product Specification

Test	Specification
Assay (H <sub>2</sub> O <sub>2</sub> )	30,0 – 32,0 %
Color (APHA)	≤ 10
Free Acid (µeq/g)	≤ 0,2
Residue after Evaporation	≤ 10 ppm
Ammonium (NH <sub>4</sub> )	≤ 3 ppm
Chloride (Cl)	≤ 0,2 ppm
Nitrate (NO <sub>3</sub> )	≤ 2 ppm
Phosphate (PO <sub>4</sub> )	≤ 1 ppm
Sulfate (SO <sub>4</sub> )	≤ 3 ppm
Trace Impurities – Aluminum (Al)	≤ 70,0 ppb
Trace Impurities – Antimony (Sb)	≤ 10,0 ppb
Trace Impurities – Arsenic (As)	≤ 10,0 ppb
Arsenic and Antimony (as As)	≤ 10,0 ppb
Trace Impurities – Barium (Ba)	≤ 20,0 ppb
Trace Impurities – Beryllium (Be)	≤ 10,0 ppb
Trace Impurities – Bismuth (Bi)	≤ 20,0 ppb
Trace Impurities – Boron (B)	≤ 10,0 ppb
Trace Impurities – Cadmium (Cd)	≤ 10,0 ppb
Trace Impurities – Calcium (Ca)	≤ 50,0 ppb
Trace Impurities – Chromium (Cr)	≤ 20,0 ppb
Trace Impurities – Cobalt (Co)	≤ 10,0 ppb
Trace Impurities – Copper (Cu)	≤ 10,0 ppb
Trace Impurities – Gallium (Ga)	≤ 20,0 ppb
Trace Impurities – Germanium (Ge)	≤ 10,0 ppb
Trace Impurities – Gold (Au)	≤ 10,0 ppb
Heavy Metals (as Pb)	≤ 500,0 ppb
Trace Impurities – Iron (Fe)	≤ 50,0 ppb
Trace Impurities – Lead (Pb)	≤ 10,0 ppb

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Trace Impurities – Lithium (Li)	≤ 10,0 ppb
Trace Impurities – Magnesium (Mg)	≤ 10,0 ppb
Trace Impurities – Manganese (Mn)	≤ 10,0 ppb
Trace Impurities – Molybdenum (Mo)	≤ 10,0 ppb
Trace Impurities – Nickel (Ni)	≤ 10,0 ppb
Trace Impurities – Niobium (Nb)	≤ 10,0 ppb
Trace Impurities – Potassium (K)	≤ 600,0 ppb
Trace Impurities – Silicon (Si)	≤ 100,0 ppb
Trace Impurities – Silver (Ag)	≤ 10,0 ppb
Trace Impurities – Sodium (Na)	≤ 100,0 ppb
Trace Impurities – Strontium (Sr)	≤ 10,0 ppb
Trace Impurities – Tantalum (Ta)	≤ 10,0 ppb
Trace Impurities – Thallium (Tl)	≤ 50,0 ppb
Trace Impurities – Tin (Sn)	190,0 – 500,0 ppb
Trace Impurities – Titanium (Ti)	≤ 10,0 ppb
Trace Impurities – Vanadium (V)	≤ 10,0 ppb
Trace Impurities – Zinc (Zn)	≤ 50 ppb
Trace Impurities – Zirconium (Zr)	≤ 10,0 ppb
Particle Count – 0.2 µm and greater	≤ 1175 par/ml
Particle Count at point of fill – 0.5 µm and greater	≤ 100 par/ml

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Hydrogen Peroxide, 30%  
CMOS  
(Stabilized)



Material No.: 2200-09

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For Microelectronic Use

Packaging Site: Paris Mfg Ctr & DC